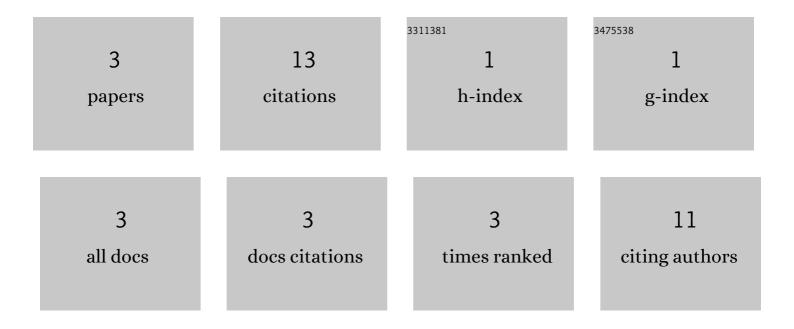
Ryo Kishida

List of Publications by Year in descending order

Source: https://exaly.com/author-pdf/2817326/publications.pdf Version: 2024-02-01



#	Article	IF	CITATIONS
1	Extracting Voltage Dependence of BTI-induced Degradation Without Temporal Factors by Using BTI-Sensitive and BTI-Insensitive Ring Oscillators. IEEE Transactions on Semiconductor Manufacturing, 2020, 33, 174-179.	1.7	11
2	Bias Temperature Instability Depending on Body Bias through Buried Oxide (BOX) Layer in a 65 nm Fully-Depleted Silicon-On-Insulator Process. , 2021, , .		1
3	An Aging Degradation Suppression Scheme at Constant Performance by Controlling Supply Voltage and Body Bias in a 65 nm Fully-Depleted Silicon-On-Insulator Process. , 2022, , .		1